

Written Test
Course code: TSEI05, Exam code: TEN1
Analog and Discrete-time Integrated Circuits (ISY)

Date:	August 22, 2009
Time:	14-18
Place:	TER1
Number of exercises:	5 (5 points max. for each exercise)
Grades:	10p for 3 (ECTS: C), 15p for 4 (ECTS: B), and 20p for 5 (ECTS:A).
Allowed material:	All types of calculators except laptops. All types of official tables and handbooks. Textbooks: Johns & Martin: Analog Integrated Circuit Design. Razavi: Design of Analog CMOS Integrated Circuits. Sedra&Smith: Microelectronic Circuits. Molin: Analog elektronik. Dictionaries.
Examiner and responsible teacher:	Sune Söderkvist
Course administrator:	Sune Söderkvist. Tel.: 281355, mail: sune@isy.liu.se
Visiting today:	Around 15.30 and 17.00 a.m.
Correct (?) solutions:	Solutions will be on the webb home page for the course.

**Graded exams are returned on examiner's office times, tuesdays and
fridays at 11.00-13.00, during week no. 37 and 38.**

Students instructions

- The CMOS transistor operation regions, small-signal parameters, and noise characteristics are found on the last page of this exam.
- Generally, do not just answer yes or no to a short question. You always have to answer with figures, formulas etc., otherwise no or fewer points will be given.
- You may write down your answers in Swedish or English.

Good Luck!

Exercise 1.

In this example we will study the small-signal properties of the capacitive-loaded amplifier in **Figure 1**. Assume that the transistors small-signal parameters are g_{m1} , g_{mbs1} , g_{ds1} and g_{m2} , g_{mbs2} , g_{ds2} respectively.

Sketch a small-signal equivalent circuit and determine an exact expression for the transfer function $H(s) = V_{out}(s)/V_{in}(s)$. The bulk effect can **not** be neglected. However, all capacitors but C_L can be neglected. Also, determine the DC gain.

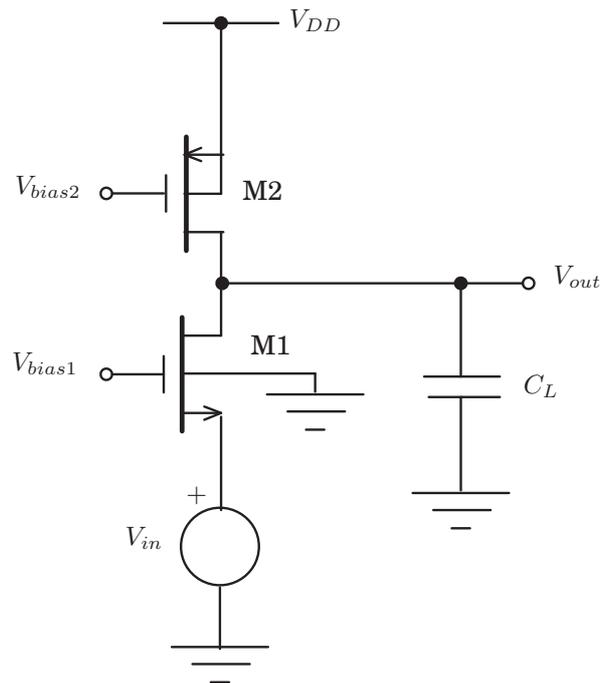


Figure 1: Gain stage.

Exercise 2.

Show that, for appropriate value of V_{bias} , equal voltage at the output and input can be obtained for the cascode stage in **Figure 2**. Assume that both transistors are operating in the saturated region. The channel-length modulation can be neglected. The transistors **M1** and **M2** have threshold voltages V_{tn} and V_{tp} respectively. The expression for V_{bias} may include V_{in} , V_{tn} and V_{tp} ; no other voltages.

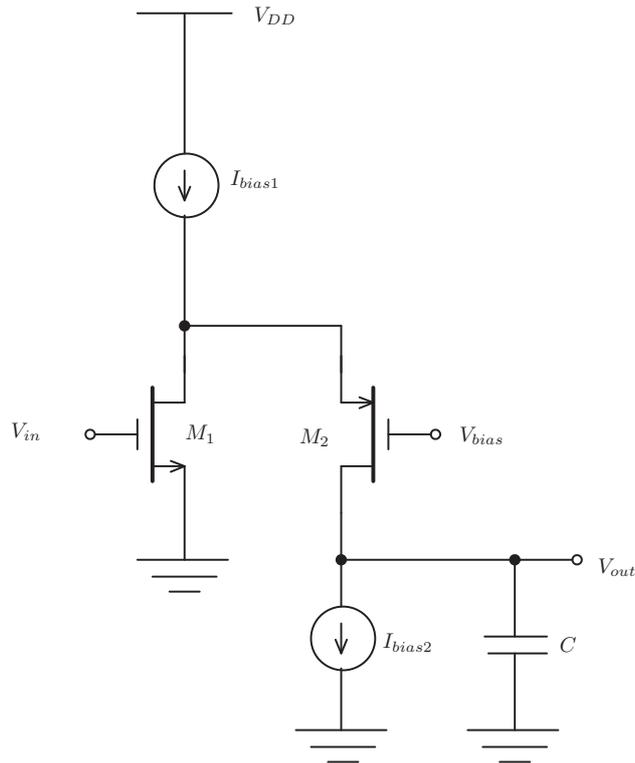


Figure 2: Folded cascode stage.

Exercise 4.

Consider the two cascaded common-source stages in **Figure 4**, where only the thermal noise generated in the transistors is of interest. The current sources are ideal and hence noiseless. Let the output load capacitance be given by C_L and parasitic capacitances are only given by gate-source capacitance, C_{gs2} , for **M2**. Further $I_{bias1} = I_{bias2} = I_{bias}$. The transistors are identical with the small signal parameters $g_{m1} = g_{m2} = g_m$ and $g_{ds1} = g_{ds2} = g_{ds}$. Both transistors operate in the saturation region.

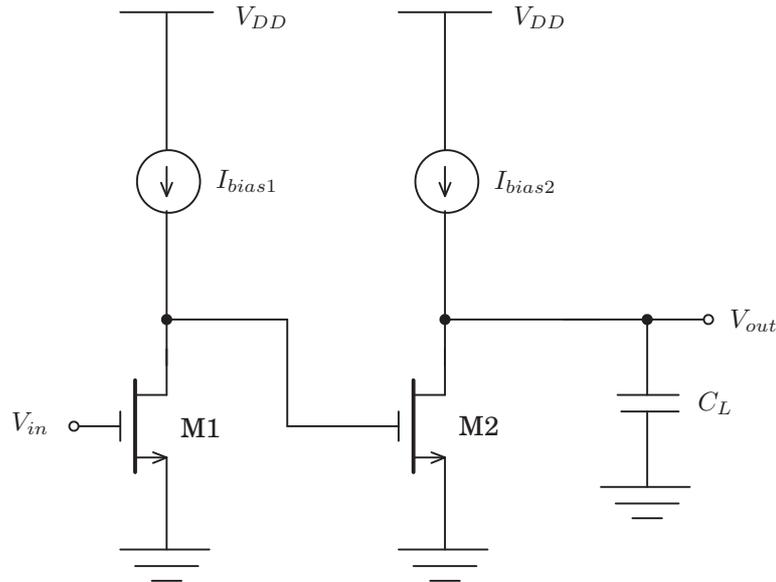


Figure 4: A noisy multi-stage amplifier.

Determine an expression for the spectral density R_{out} of the output thermal noise assuming that the noise from the transistors are uncorrelated.

Exercise 5.

Assume that the TV-signal comes by a 75 ohm wire from the antenna. Your task here is to design a box that splits the signal into two rooms without giving any reflection. Are there any disadvantages with your construction?

Transistor formulas and noise

1 CMOS transistors

Current and threshold voltage formulas and operating regions for an NMOS transistor

$$\begin{aligned} \text{Cut-off:} \quad & V_{GS} < V_t & I_D &\approx 0 \\ \text{Linear:} \quad & V_{GS} - V_t > V_{DS} > 0 & I_D &= \alpha(2(V_{GS} - V_t) - V_{DS})V_{DS} \\ \text{Saturation:} \quad & 0 < V_{GS} - V_t < V_{DS} & I_D &= \alpha(V_{GS} - V_t)^2(1 + \lambda(V_{DS} - V_{eff})) \\ & & & V_{DSsat} = V_{eff} = V_{GS} - V_t \\ \text{All regions:} \quad & V_t = V_{t,0} + \gamma(\sqrt{2\phi_F - V_{BS}} - \sqrt{2\phi_F}) \end{aligned}$$

Small-signal parameters

$$\begin{aligned} \text{Linear:} \quad & g_m \approx 2\alpha V_{DS} \quad g_{ds} \approx 2\alpha(V_{GS} - V_t - V_{DS}) \\ \text{Saturation:} \quad & g_m \approx 2\sqrt{\alpha I_D} \quad g_{ds} \approx \lambda I_D \end{aligned}$$

$$\text{Constants:} \quad \alpha = \frac{1}{2}\mu_{0n}C_{ox}\frac{W}{L} \quad \lambda = \sqrt{\frac{K_s\epsilon_0}{2qN_A\phi_0}} \cdot \frac{1}{L} \quad \gamma = \frac{\sqrt{2qN_AK_s\epsilon_0}}{C_{ox}}$$

2 Circuit noise

Thermal noise in CMOS transistors

The thermal noise spectral density at the gate of a CMOS transistor is

$$V^2(f) = \frac{8kT}{3} \cdot \frac{1}{g_m}$$

Thermal noise in resistors

The thermal noise spectral density of a resistor is modeled as a parallel noise current source

$$I^2(f) = \frac{4kT}{R}$$

Flicker noise in CMOS transistors

The flicker noise spectral density at the gate of a CMOS transistor is

$$V^2(f) = \frac{K}{WLC_{ox}f}$$